

# SiW ECAL: the status before Fermilab

Marcel Reinhard  
LLR – Ecole Polytechnique













CALICE collaboration meeting 18/03/08, Argonne

# Outline

- Wishlist Prague
- What happened since Prague?
- Some issue to tackle
- What will happen until Fermilab?



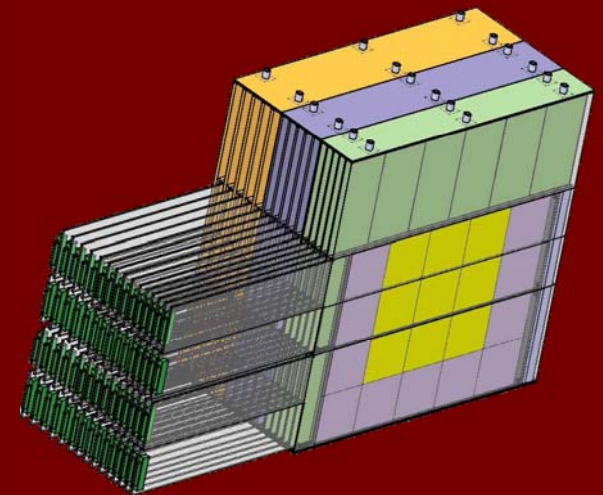
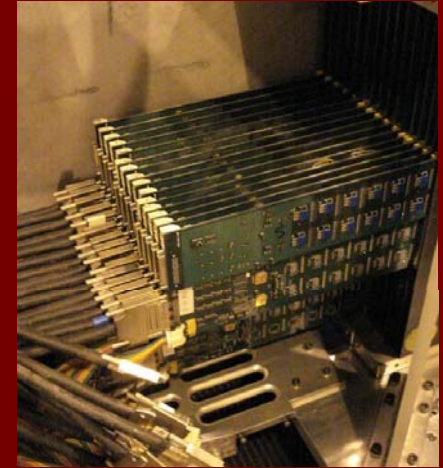
# Wishlist of Prague

-  • Solution to instable pedestals (improved regulators?)
-  • Revisions of bottom slabs
-  • Spare power cables and maybe a test of the existing cables + new ones will be needed when the detector is completed
-  • Data of ECAL slow control should be included in data stream (the most useful would be currents and voltage at each wafer)
-  • Improved accessibility of ECAL cables (for now removing the fans requires moving the ECAL out of its nominal center – time consuming)
-  • Revision of program for control of ECAL stage
-  • ECAL position on stage in database
-  • Online Monitor:
  - Possibility to limit visualisation to center/upper part
  - Correction for moving pedestals ?
-  • Possibility to improve the space available for ECAL rotation?
-  • DESY test with all experts on site (with beam if possible!)



# Reminder: configuration in the CERN 2007 TB

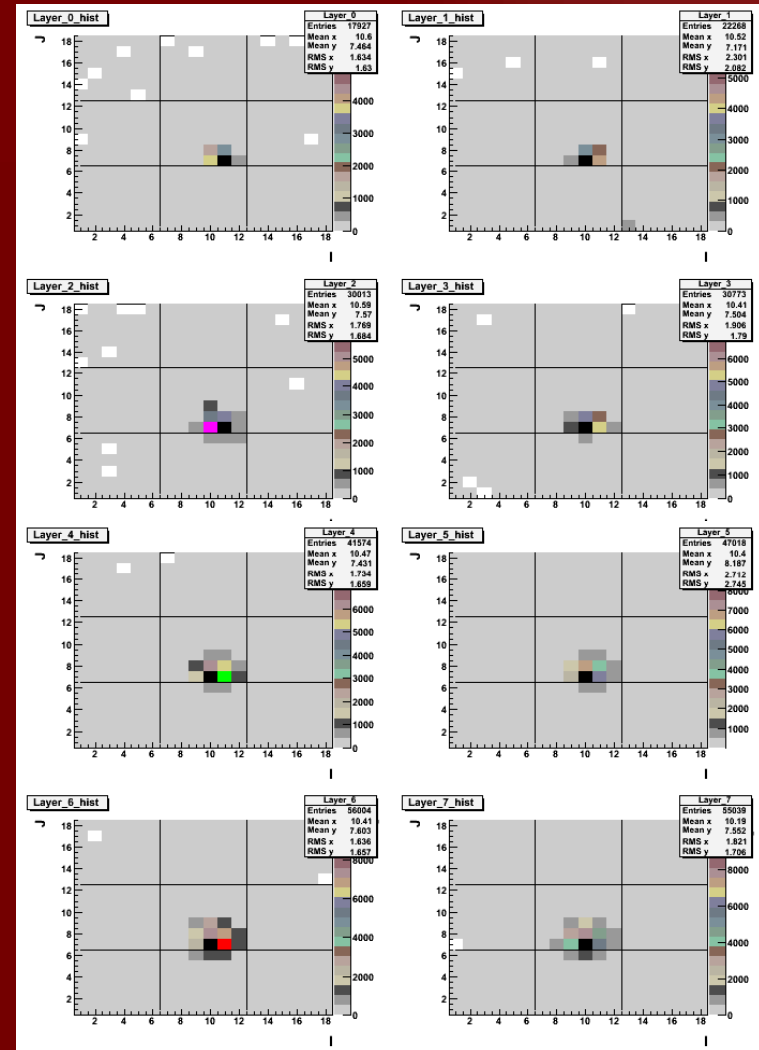
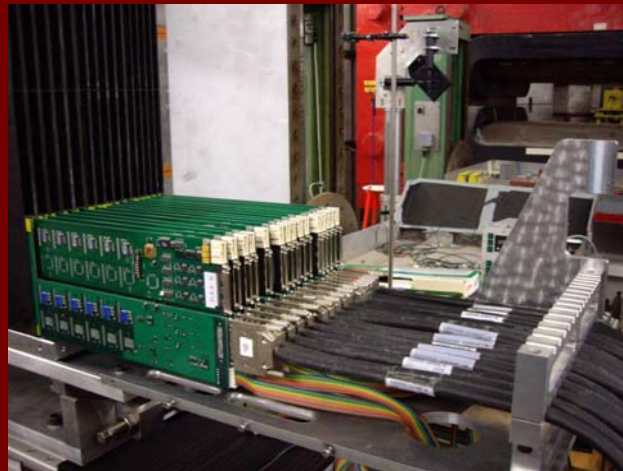
- Center part fully equipped (30 layers, 6480 channels)
- Bottom part (equipped subsequently from back to front):
  - June 23<sup>rd</sup>: 12 layers
  - July 4<sup>th</sup>: 6 more layers added
  - July 26<sup>th</sup>: 6 more layers added, tungsten dummies in empty slots  
-> 24 layers, 2592 channels
- 9072 channels in total



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# Tests at DESY 12/07

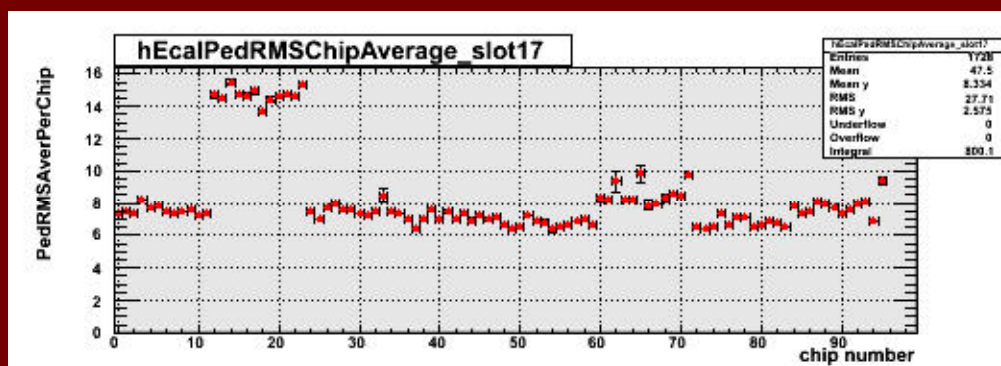
- ECAL fully equipped: 9720 cells
- Some beam data to validate additional bottom slabs
- Electronics tests revealed weaknesses of patch panel as source of noise problems



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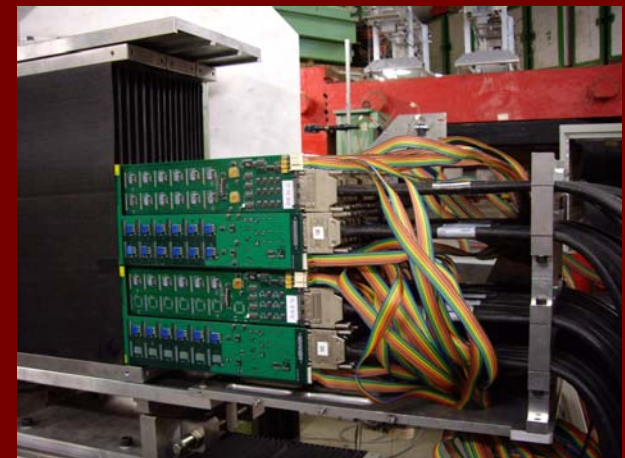
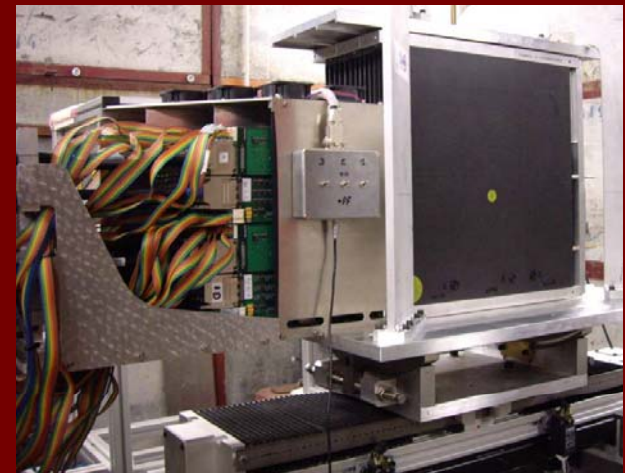
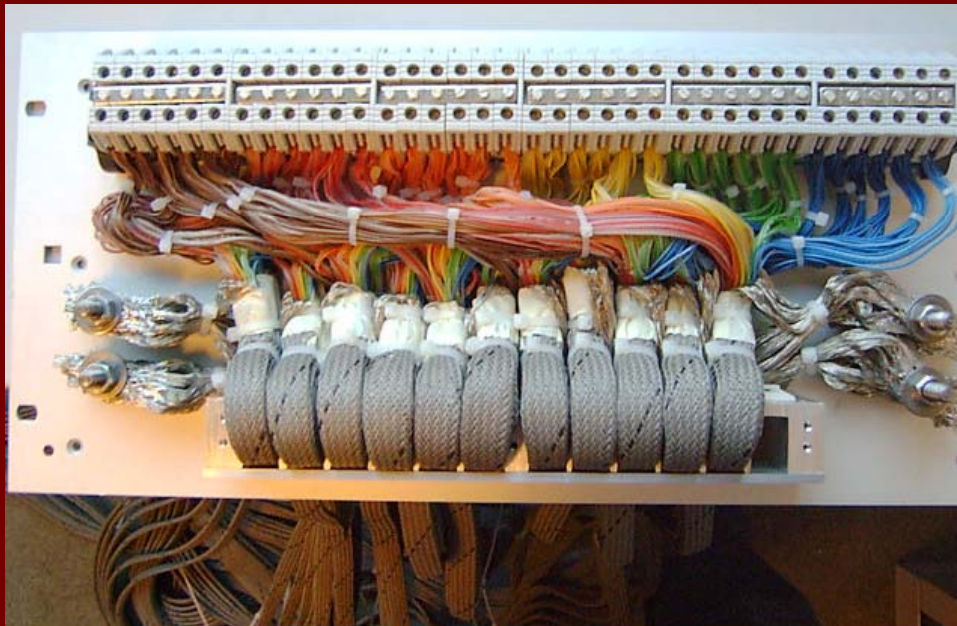
# Reminder: Noise problems

- All noise values for the cells on a PCB are too high
- Very sensitive to the delivered power, thus to the power supplies and/or the power cables
- Changing of power cable can solve the problem
- Several cables marked as „problematic“
- Noise varying with positioning of patch panel




# New Patch Panel

- Built from scratch
- All Power cables with extra shielding
- Ground of all cables connected on the detector side
- Big thanks to Patrick Cornebise From LAL



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# Electronics and integration tests at DESY 02/08

- Complete mounting on the new AHCAL stage
- Installation of new patch panel and routing of power cables
  - Noise tests prove new pp a complete success
- Big thank you to Jean-Charles Vanel & Patrick Cornebise

## On the way to Fermilab

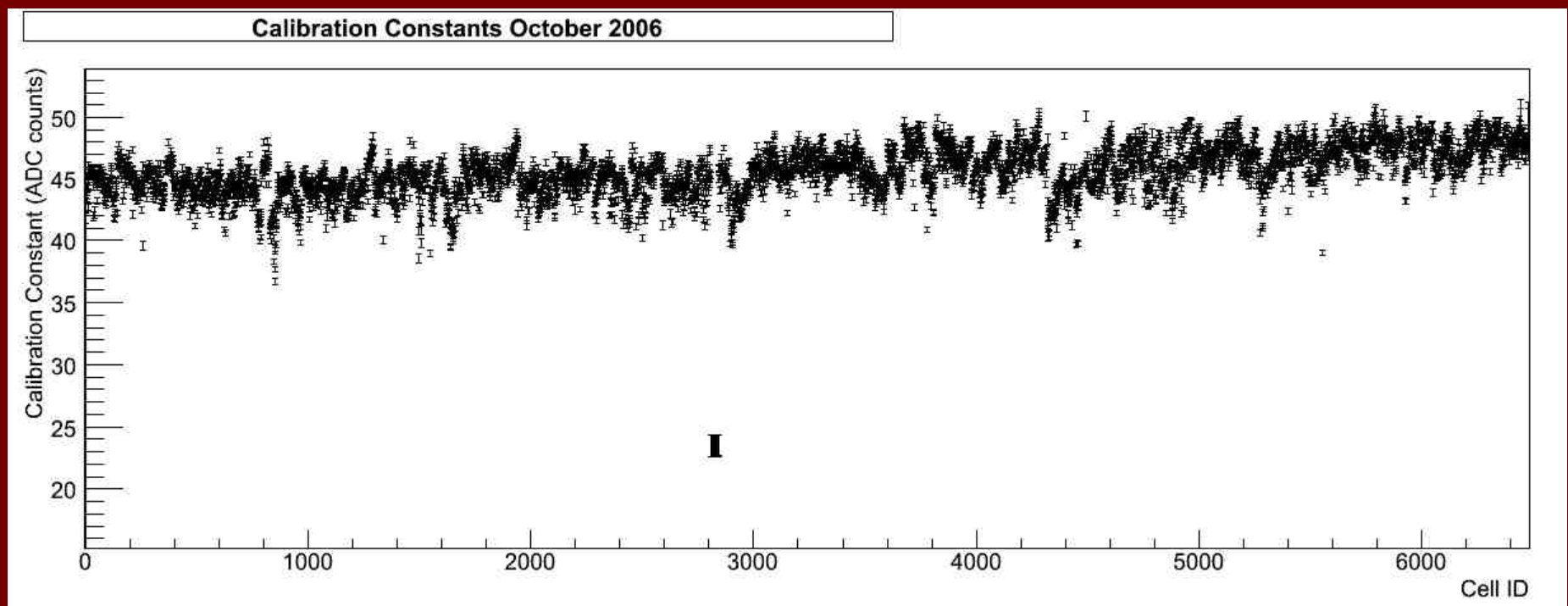
- Shipment prepared
  - ECAL support stays on AHCAL stage
  - Slabs and W structure in their boxes
- Installation at Fermilab:
  - Start at 21<sup>st</sup> of April





# Some issue: Focus on calibration studies

- Currently in database: 1 set of constants obtained with muon runs from october 2006 CERN period

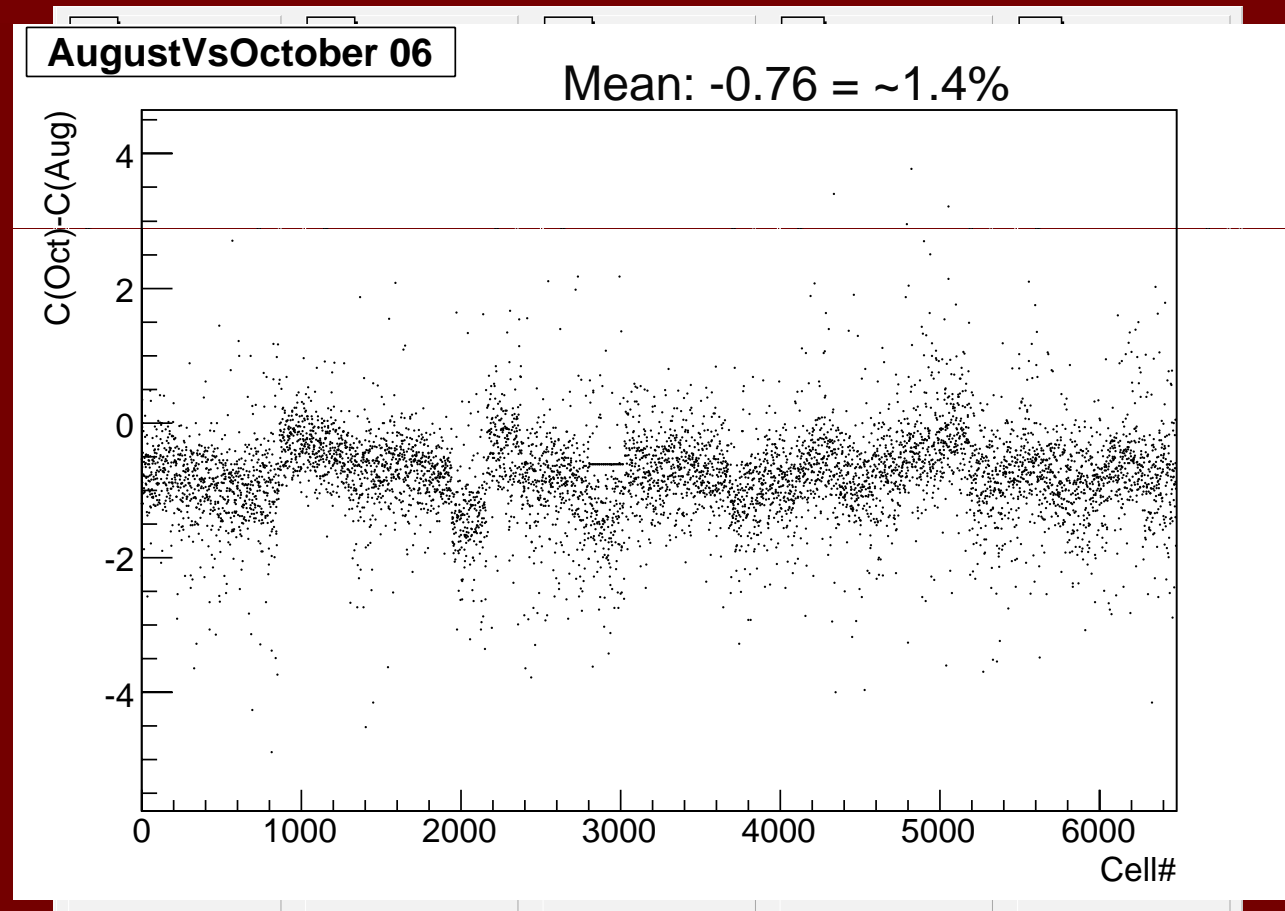


- Now additionally: constants for 3 other periods (August 2006, July 2007 (0 deg), August 2007 (20 deg))

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# August 2006

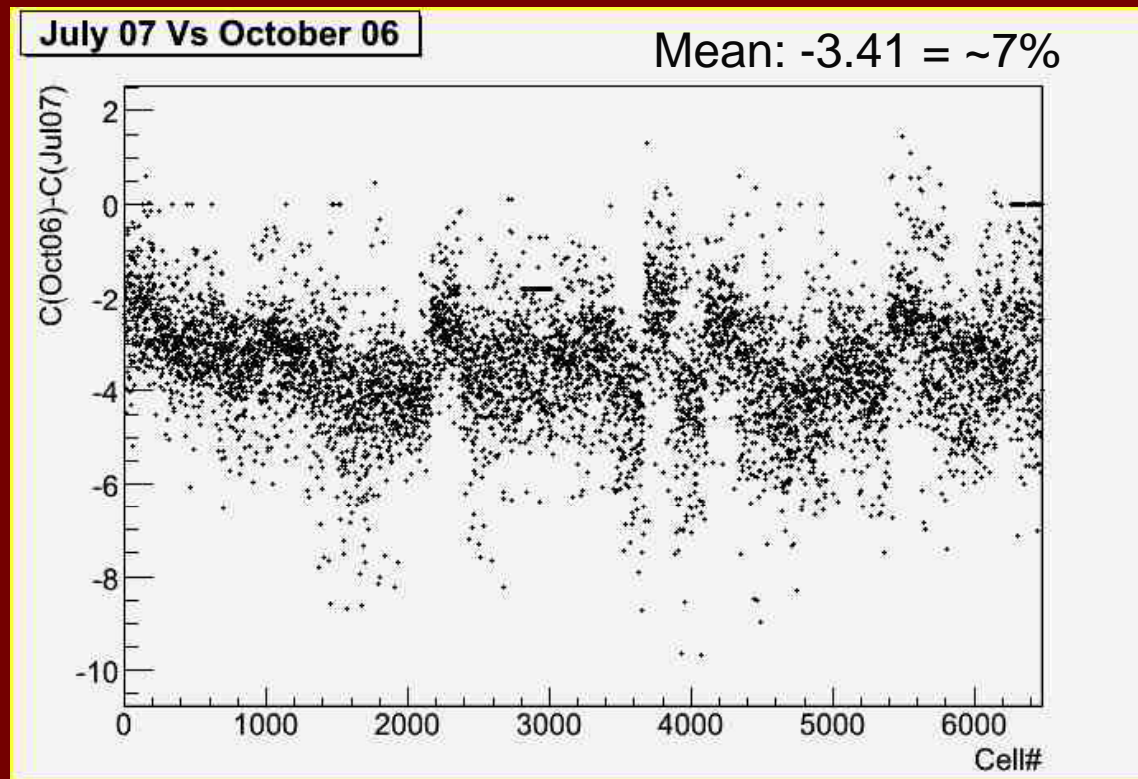
- Dead map looks good
- Significant systematic shift of calibration values



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# July 2007 (0 deg): central slabs

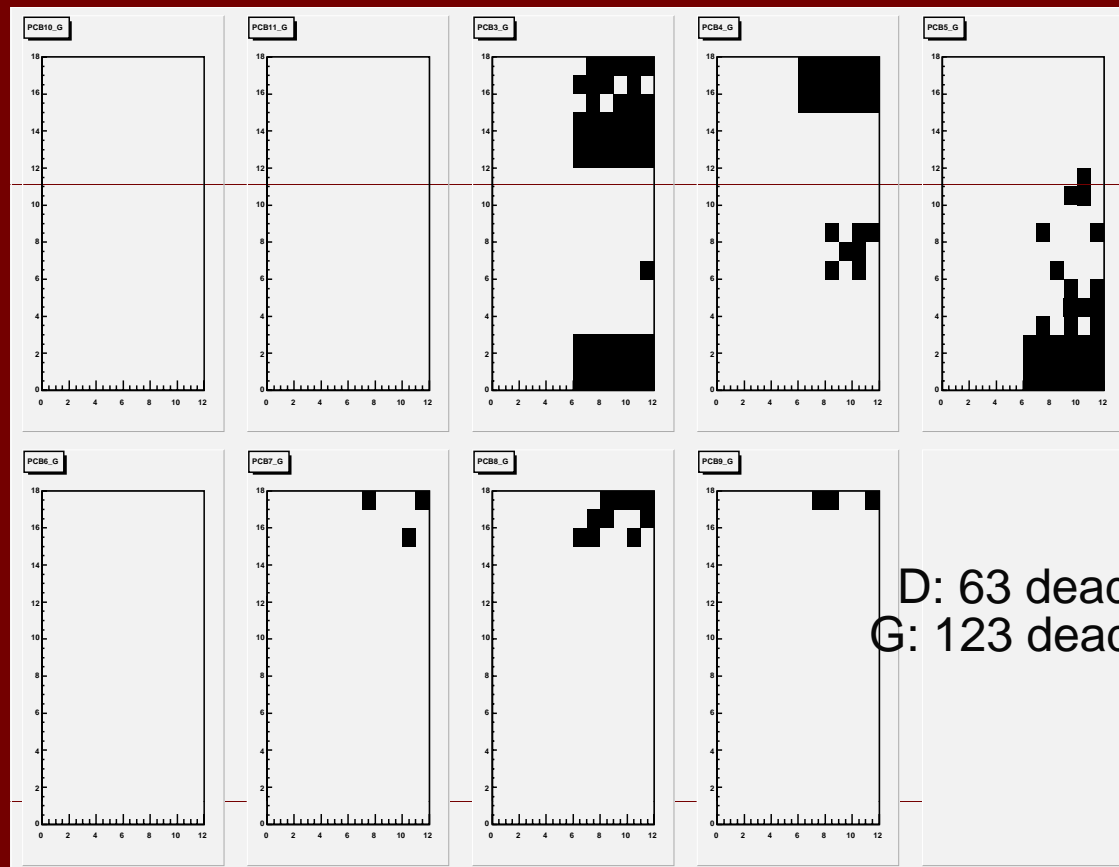
- Dead map looks ok, readout problem of last layer, 44 dead
- Confirms data quality checks in Prague
- Significant systematic shift of calibration values
- Few slabs with less effect: influence of old patch panel ?



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# July 2007 (0 deg): bottom slabs

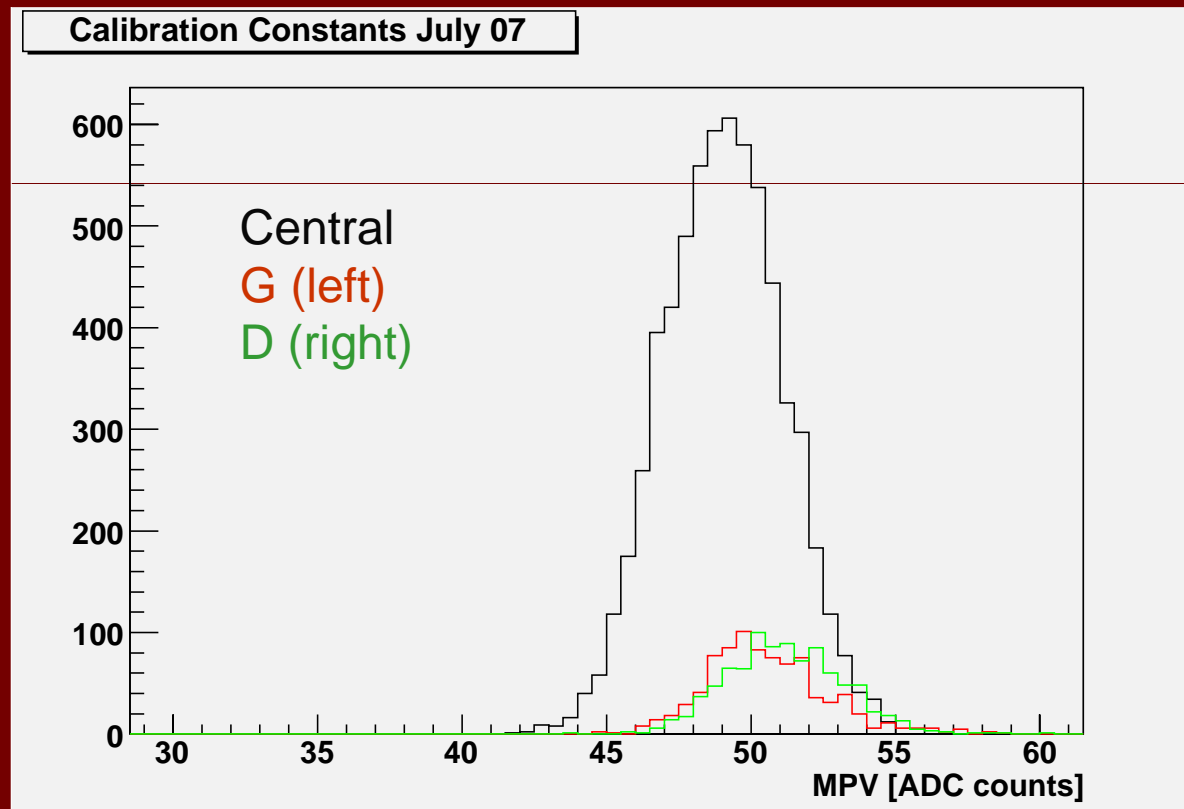
- Quite some dead cells, even entire chips
- Confirms data quality checks in Prague



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# July 2007 (0 deg)

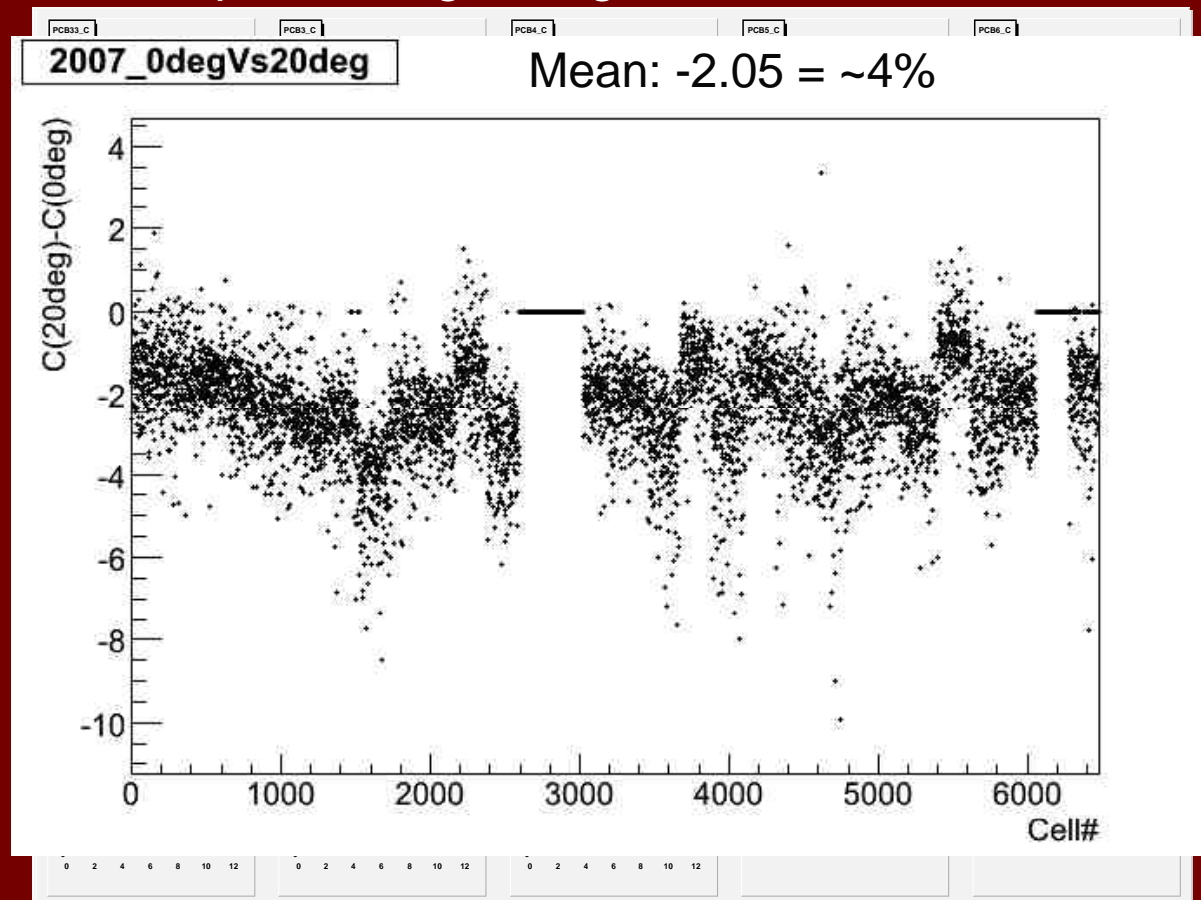
- Shift in peak between central and bottom (wafer production)
- Shift between left- and right-handed slabs (?)



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# Aug 2007 (20 deg): central slabs

- More dead channels than before rotation, additional r/o problem, 141 dead
- Higher values expected, again significant shift

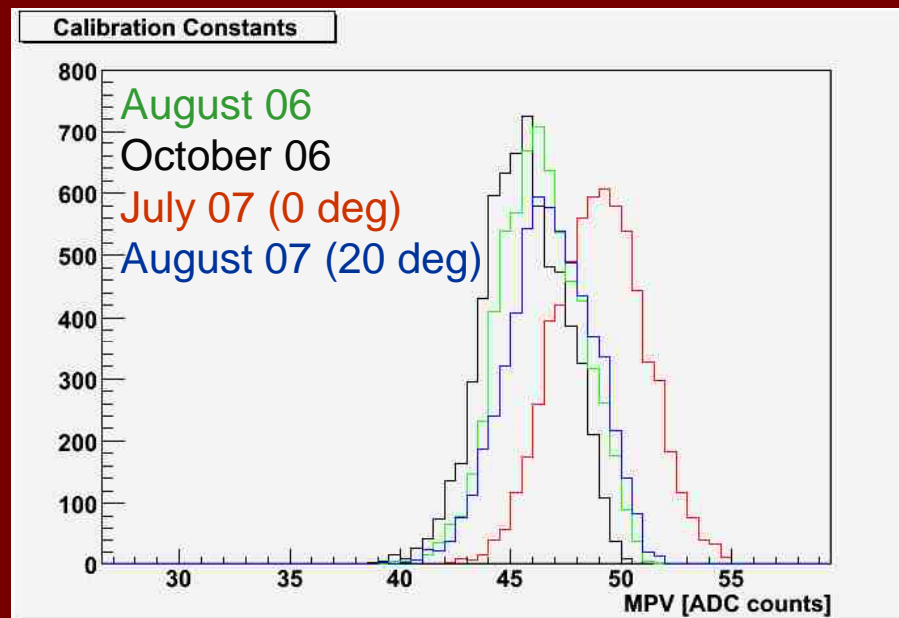


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# Calibration Constants overview central slabs













- Significant shifts between all periods – why? Not seen in e- runs
- Si diodes known to be stable regarding temperature, operated on saturation plateau at 200V
- 2 (?) possibilities
  - 1<sup>st</sup>: Hold Value/Trigger issues (same setup in Jul/Aug 07 !)
  - 2<sup>nd</sup>: stability of on-board electronics (gain variation with Temp and Voltage)



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# ...to come back to this:

-  Solution to instable pedestals (improved regulators?)
-  Revisions of bottom slabs
-  Spare power cables and maybe a test of the existing cables + new ones will be needed when the detector is completed
-  Data of ECAL slow control should be included in data stream (the most useful would be currents and voltage at each wafer)
-  Improved accessibility of ECAL cables (for now removing the fans requires moving the ECAL out of its nominal center – time consuming)
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-  DESY test with all experts on site (with beam if possible!)





# Conclusion

- ECAL ready for data taking at Fermilab
- New patch panel eliminates noise problems
- ECAL slow control monitoring during all the test period obligatory
- Tackle dead cells: chips and read-out problems
- Need faster feedback to identify r/o problems
- Should find reasons of changes in Calibration Constants
- 3 calibration sets for now (Aug06/Oct06/Jul07) – which to use for next reconstruction?



# Backup

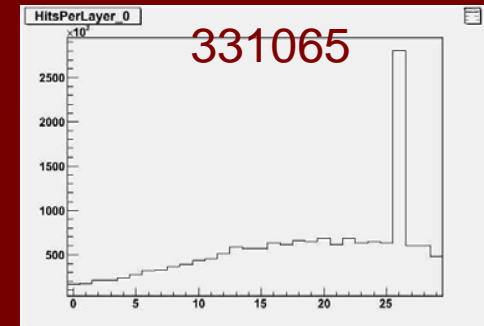
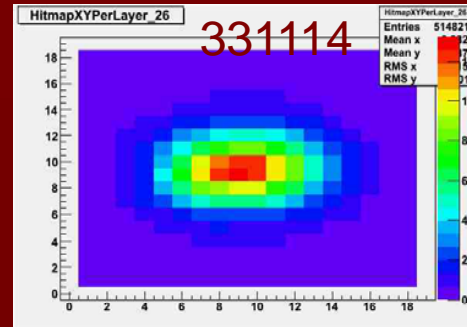
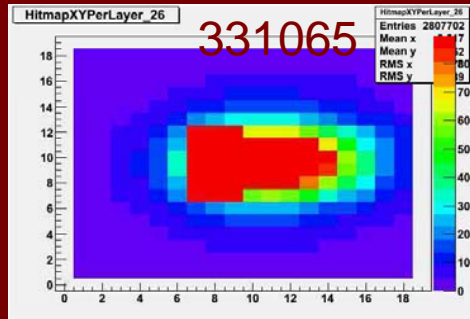


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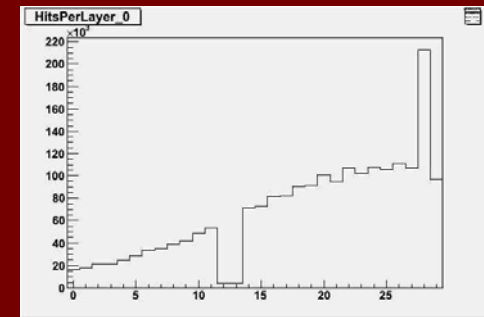
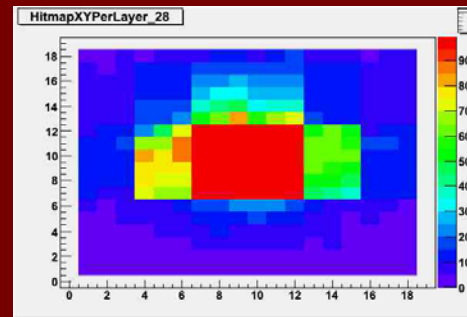
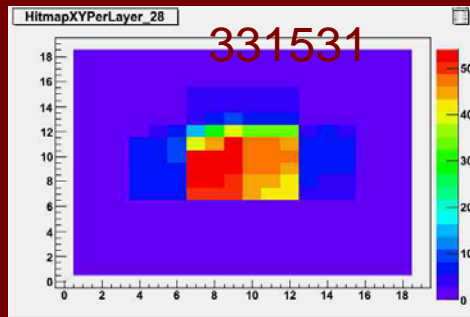
# Noisy chips

- Some chips can develop higher noise for a certain period in time

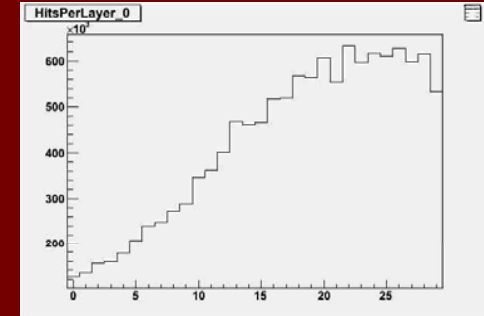
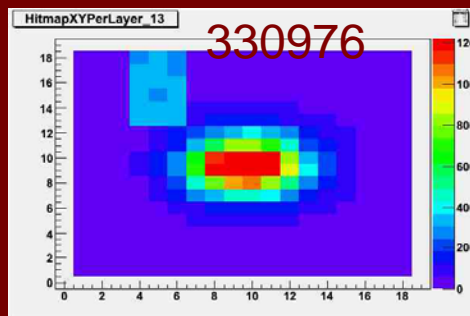
Layer 26



Layer 28

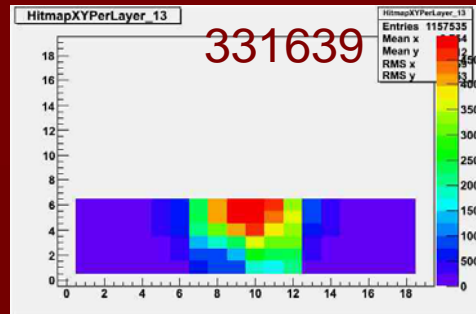


Layer 13

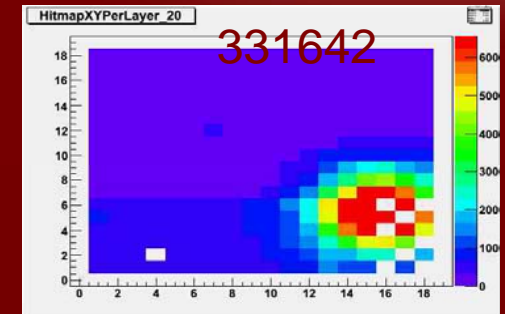



# Behavior of bottom slabs

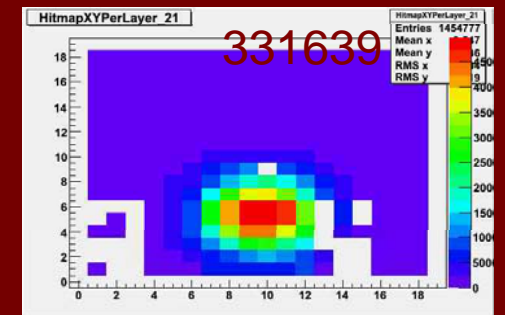
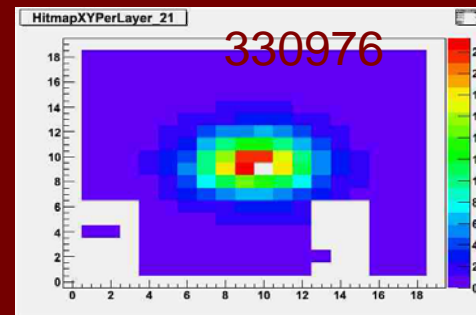
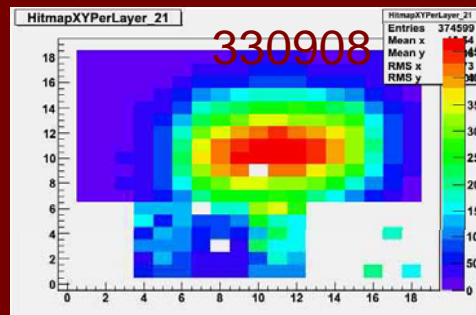
Layer 13



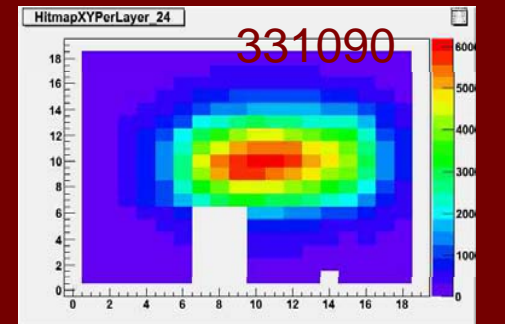
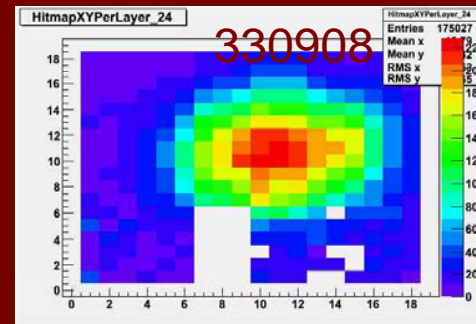
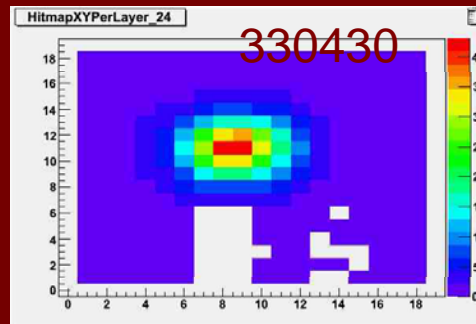
Layer 20



Layer 21



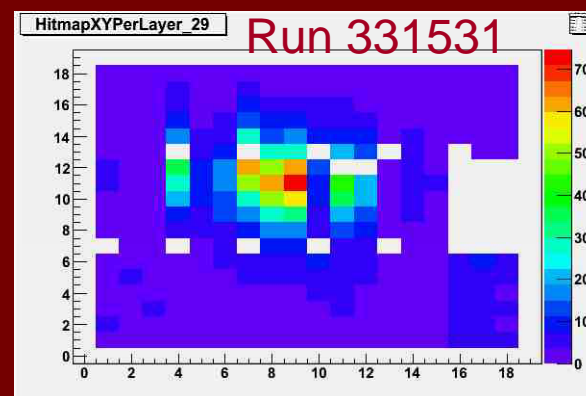
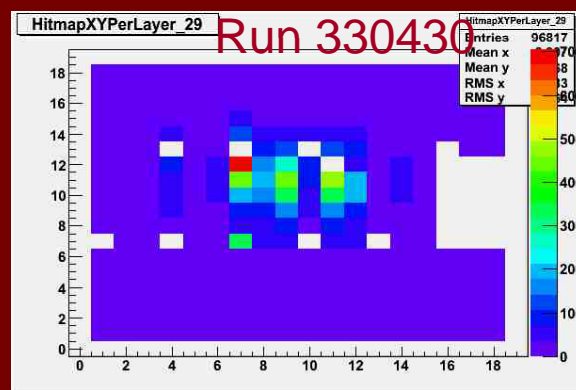
Layer 24



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# Problems due to the connectors (?)

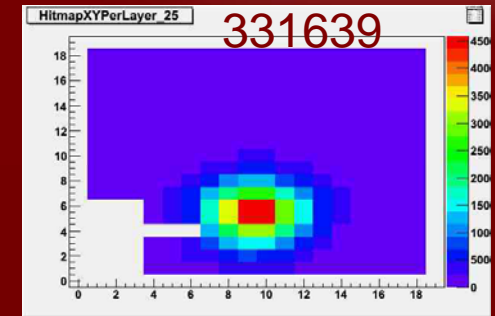
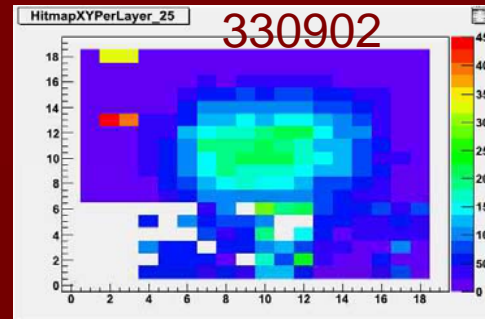
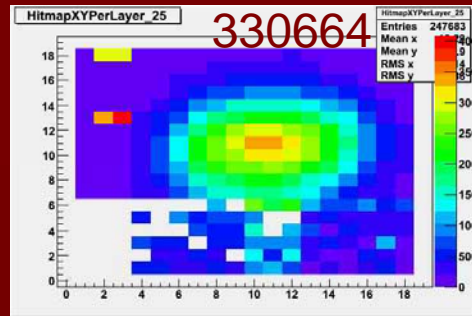
- Can cause noise in several cells
- Typical structure that one chip is not connected
- In some cases is the access impossible due to limited space
- No guarantee by de- and replugging
- Read-out problems (?)



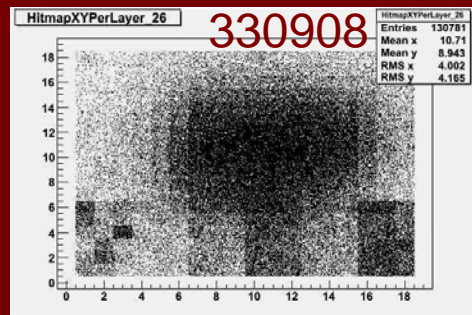
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# More bottom slabs

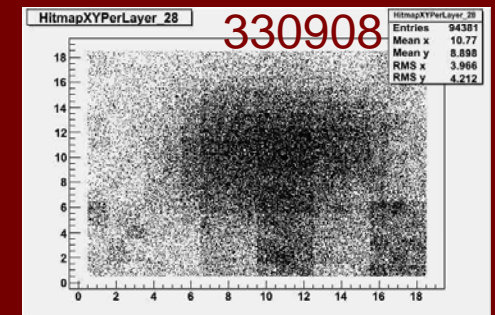
Layer 25

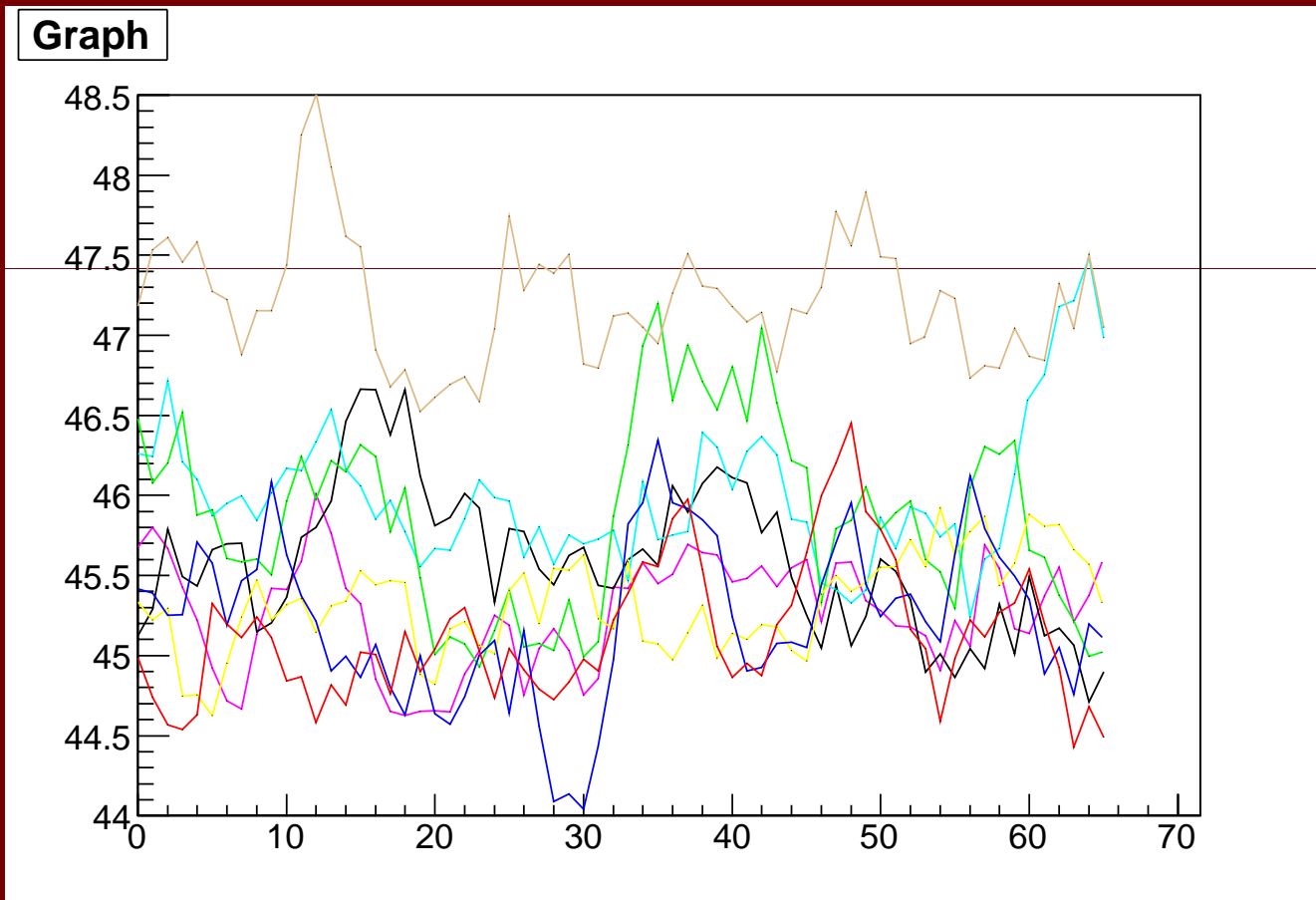


Layer 26



Layer 28

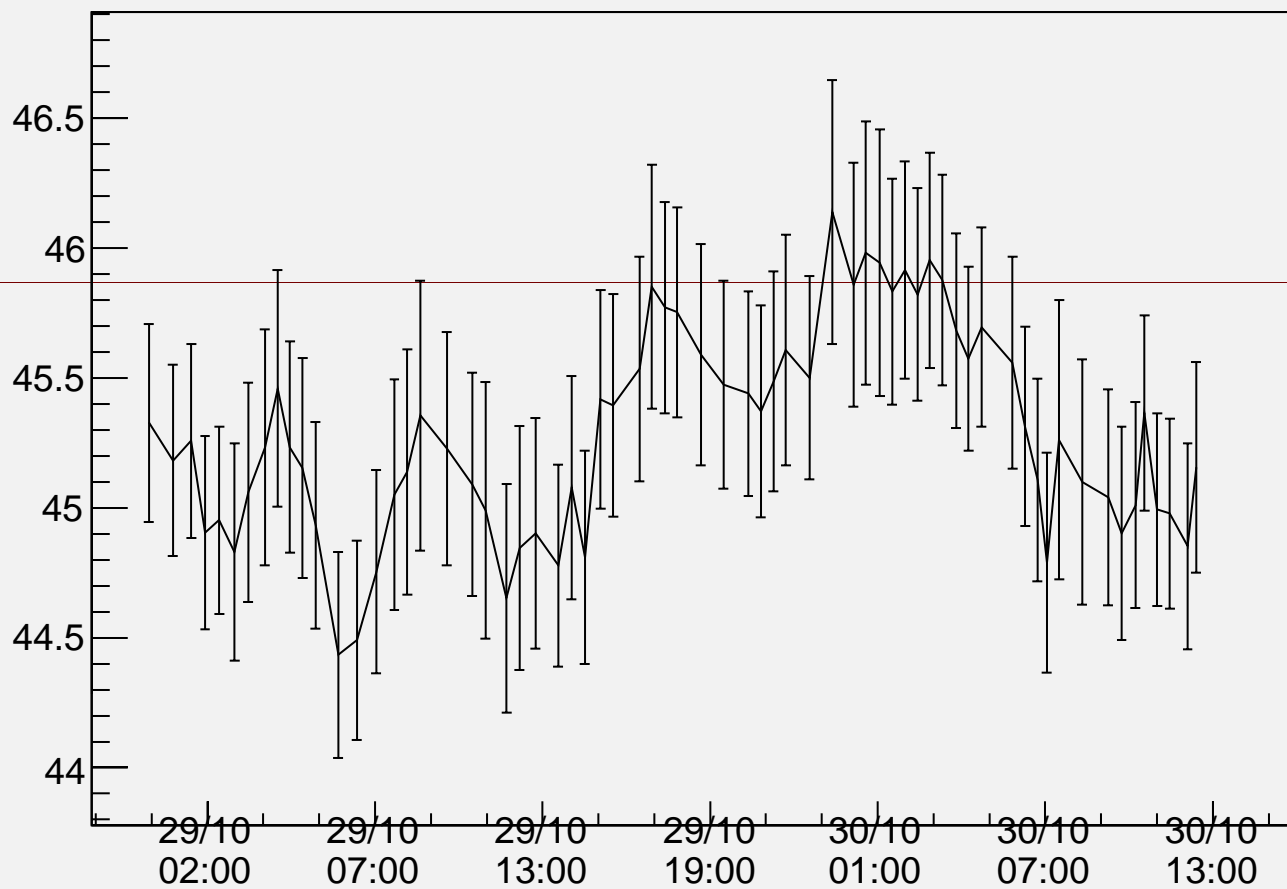




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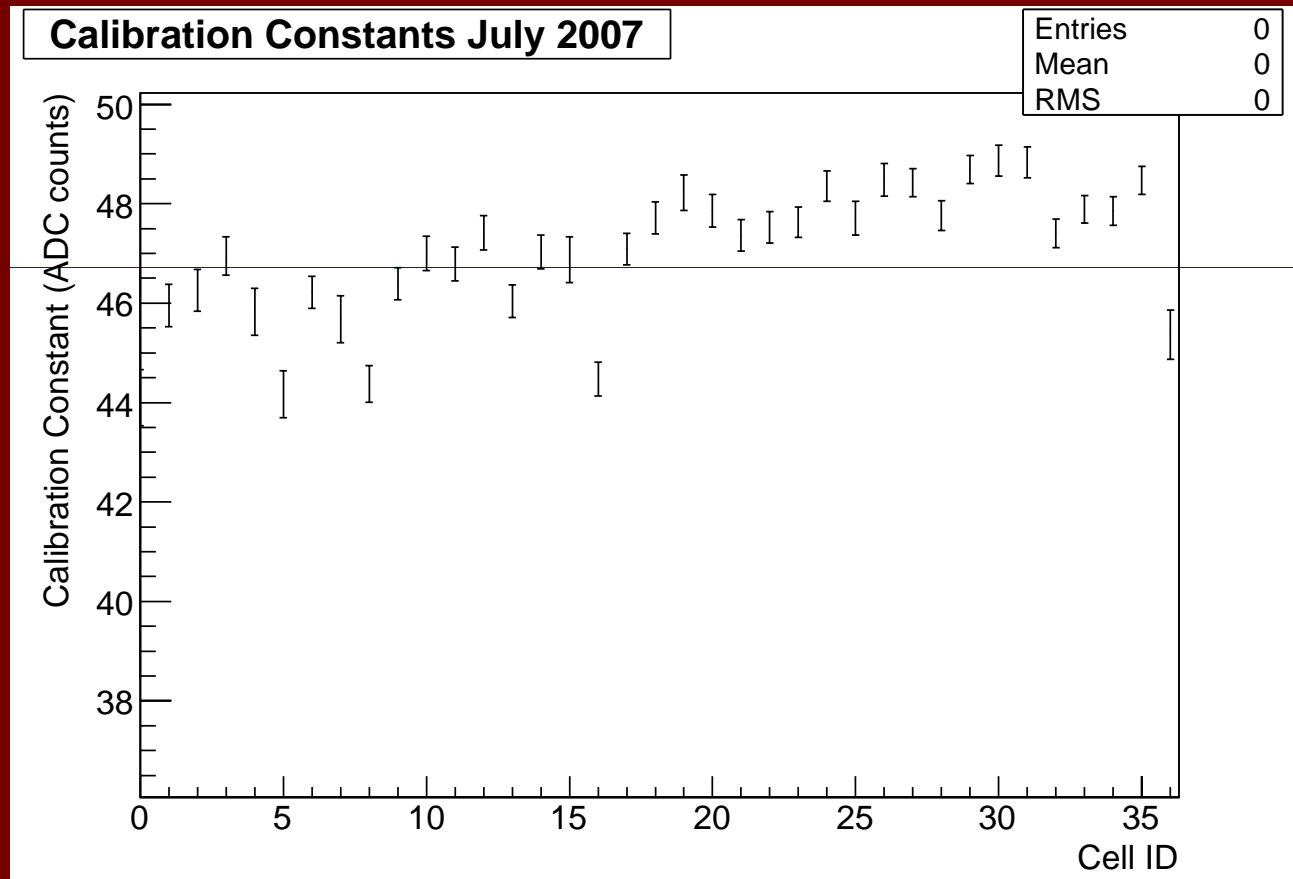
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Graph



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